IFICLS (IFI Current Patent Legal Status Database)

Subject Coverage	- Reassigned U.S. patents from 1980 to the present - Reexamined U.S. patents from 1981 to the present - Extended U.S. patents from late 1985 to the present - Expired U.S. patents from September 1985 to the present - Reinstated U.S. patents from September 1985 to the present - Adverse decision records from 1980 to the present Disclaimer/dedication records from 1980 to the present - Reexamination request records from 1980 to the present - Reissue request records from 1985 to the present - Certificates of correction

File Type Bibliographic

Features

Thesaurus	None				
Alerts (SDIs)	Weekly (default), monthly, bimonthly				
CAS Registry Number® Identifiers	☐	Page Images	☐	STN® AnaVist™	☐
Keep & Share	☑	SLART	☐	STN Easy®	☐
Learning Database	☐	Structures	☐		

Record Content

- Current legal status of U.S. patents. It includes reassigned patents (when the ownership of a patent is transferred from the original assignee to another company or individual), reexamined patents (patents that have undergone a review by the U.S. Patent and Trademark Office (USPTO) due to substantial new questions regarding the patentability of the patent's claims), patents extended beyond their normal 20-year term, expired patents, and reinstated patents.
- Adverse decision in interference, disclaimer/dedication information, reexamination request, reissue request, reissued patents, and certificate of correction.
- Patent number, former assignee, new assignee, reassignment type, e.g., full interest, date of reassignment, and reel and frame number of the USPTO microfilm record.
- Reexamination records include the patent number, patent assignee, name and location of the party requesting reexamination, reexamination request number and date, and reexamination certificate number and date. Text from the reexamination certificate describing the results of the reexamination is also included.
- Extension, expiration, and reinstatement records include the patent number, patent assignee, expiration, extension, or reinstatement date, and publication date of the *Official Gazette* of the USPTO containing the announcement of action.
- Reexamination request records include patent assignee, patent information, and reexamination request information. Adverse decision records include patent assignee, patent information, and adverse decision information. Disclaimer/dedication records include patent assignee, patent information, and disclaimer information. Reissue request records include patent assignee, patent information, reissue request information, and reissue patent numbers. Records for certificate of correction include patent assignee, patent information, and correction date.

File Size More than 5.4 million records (08/19)

Coverage 1980-present

Updates	Updated weekly
Language	English
Database Producer	IFI CLAIMS® Patent Services, a division of Fairview Reseach LLC P.O. Box 1148, Madison, CT 06443 Phone: (203) 779-5301 Fax: (203) 583-4521 Email: info@ificlaims.com
Sources	The U.S. Patent and Trademark Office
User Aids	• Online Helps (HELP DIRECTORY lists all help messages available) • STNGUIDE
Clusters	• ALLBIB • HPATENTS • PATENTS STN Database Clusters information (PDF).
Related Databases	• IFIALL • IFIREF
Pricing	Enter HELP COST at an arrow prompt (=>).

SEARCH and DISPLAY Field Codes

There are no fields that allow left truncation.

Search Field Name	Search Code	Search Examples	Display Codes
Basic Index (contains single words from the adverse decision text (ADTX), disclaimer/dedication text (DDTX), and patent claim text for reexamined patents (CLM) fields)	None (or /BI)	S ALKOXY? S ALKYL RADICAL# S DISCLAIMER#	ADTX, CLM, DDTX
Accession Number	/AN	S 1878343/AN	AN
Adverse Decision Date **(1)**	/ADD	S APR 7, 2005/ADD	ADD
Adverse Decision Number	/ADN	S 103473/ADN	ADN
Correction Date **(1)**	/CDAT	S 20040601/CDAT	CDAT
Disclaimer/Dedication Date **(1)**	/DDD	S 20010904/DDD	DDD
Document Type (code and text)	/DT (or /TC)	S EXPIRED/DT S XP/DT	DT
Entry Date **(1)**	/ED	S 20040511/ED	Not displayed
Expiration Date **(1)**	/XPD	S 20020700-20031100/XPD	XPD
Extension Date **(1)**	/XTD	S XTD> 19940401	XTD
Field Availability	/FA	S CLM/FA	Not displayed
Language (code and text)	/LA	S ENGLISH/LA	Not displayed
Official Gazette Issue Date with Adverse Decision **(1)**	/ADG	S 20050222/ADG	ADG
Official Gazette Issue Date with Disclaimer/Dedication Date **(1)**	/DDG	S NOV 13 2001/DDG	DDG
Official Gazette Issue Date with Expiration Announcement **(1)**	/XPG	S XPG>19970901 S XPG>SEP 1, 1997	XPG
Official Gazette Issue Date with Extension Announcement **(1)**	/XTG	S XTG>19950900	XTG
Official Gazette Issue Date with Reexamination Request **(1)**	/RQG	S 19960903/RQG	RQG
Official Gazette Issue Date with Reinstatement Announcement **(1)**	/RIG	S RIG>=19971123 S RIG>=NOV 23, 1997	RIG
Official Gazette Issue Date with Reissue Request **(1)**	/REG	S 19951205/REG	REG
Patent Assignee **(2)**	/PA (or /CS)	S KODAK/PA S DOW CORNING/PA	PA, RAC
Patent Assignee, Original **(2,3)**	/PAO	S BRAUN/PAO	PAO
Patent Country	/PC	S US/PC	PI
Patent Number **(4,5)**	/PN	S US4893422/PN S US33420/PN	PI, PN
Publication Date **(1)**	/PD	S 19900116/PD	PI
Publication Year **(1)**	/PY	S PY>=1997	PI
Reassignment Address **(2)**	/RAA	S KENYON/RAA	RAA
Reassignment Company **(2)**	/RAC	S UPJOHN/RAC	RAC
Reassignment Date **(1)**	/RAD	S 20030811/RAD	RAD
Reassignment Kind **(2)**	/RAK	S FULL/RAK	RAK
Reexamination Certificate Date **(1)**	/RXD	S 19900410/RXD S RXD>=19920630	RXD
Reexamination Date **(1)**	/RRD	S 19920218/RRD	RRD
Reexamination Numbers	/RXN	S B14769435/RXN	RXN
Reexamination Request Date **(1)**	/RQD	S 19960802/RQD	RQD
Reexamination Request Number	/RQN	S 90/004321/RQN	RQN
Reexamination Request Requestor **(2)**	/RQR	S ELECTRA/RQR	RQR
Reexamination Requestor **(2)**	/RXR	S DOW CHEMICAL/RXR	RXR
Reinstatement Date **(1)**	/RID	S RID>19930500	RID
Reissue Examination Group	/REX	S 1107/REX	REX

SEARCH and DISPLAY Field Codes (cont'd)

Search Field Name	Search Code	Search Examples	Display Codes
Reissue Request Date (1)	/RED	S 20040213/RED	RED
Reissue Request Number	/RRN	S 06/026465/RRN	RRN
Update Date (1)	/UP	S 20040420/UP	Not displayed
Update Date, Correction Data (latest IFI update to Correction Data) (1)	/UPCD	S 19990703/UPCD	UPCD
Update Date, Reassignment Data (latest IFI update to Reassignment Data) (1)	/UPRAI	S 20010320/UPRAI	UPRAI
Update Date, Status Information (latest IFI update to the Status Information) (1,6)	/UPSTA	S 19990720/UPSTA	UPSTA

(1) Numeric search field that may be searched with numeric operators or ranges.
(2) Search with implied (S) proximity is available in this field.
(3) This field contains data only for reassigned patents.
(4) Either STN or Derwent format may be used.
(5) Reissue patent numbers are searchable in the field.
(6) This field contains the latest IFI update to the Status Information other than Certificate of Correction or Reassignment Actions. This includes Expirations, Extensions, Reinstatements, Adverse Decisions, Disclaimer/Dedications, Request for Reexamination, Requests for Reissue, and Reexaminations.

Super Search Fields

Enter a super search code to perform a search in one or more fields that may contain the desired information. Super search fields facilitate crossfile and multifile searching. EXPAND may not be used with super search fields. Use EXPAND with the individual field code instead.

Search Field Name	Search Code	Fields Searched	Search Examples	Display Codes
Patent Assignee Group	/PASS	/PA, /PAO, /RAC	S MIT/PASS	PASS
Patent Countries	/PCS	/DS, /FC, /PC	S US/PCS	PI
Patent Numbers (1,2)	/PATS	/FN, /PN	S US4893422/PATS	PI, PN

(1) Either STN or Derwent format may be used.
(2) Reissue patent numbers are searchable in the field.

DISPLAY and PRINT Formats

Any combination of formats may be used to display or print answers. Multiple codes must be separated by commas or spaces, e.g., D L3 1-10 PI,PA or D L3 1-10 PI PA. The fields are displayed or printed in the order requested.

Hit-term highlighting is available in AND, ADTX, CDAT, CLM, DDTX, DT, PA, RQN, RRN, and RXN. Highlighting is set ON by default and must be ON when SEARCH is performed in order to use the HIT, KWIC, and OCC formats.

Format	Content	Examples
AN **(1)**	Accession Number	D L4 5 AN
ADD	Adverse Decision Date	D 1,3 ADD
ADG	Official Gazette Issue Date with Adverse Decision	D ADG 1-5
AND	Adverse Decision Number	D AND
ADTX	Adverse Decision Text	D ADTX
CDAT	Correction Date	D CDAT
CLM	Patent Claim Text	D 7 CLM
DDD	Disclaimer/Dedication Date	D DDD
DDG	Official Gazette Issue Date with Disclaimer/Dedication Date	D DDG
DDTX	Disclaimer/Dedication Text	D DDTX
DT (TC)	Document Type	D 1-4 DT
PA (CS)	Patent Assignee	D L2 1-3 PA
PAO	Patent Assignee, Original	D PA, PAO
PI **(1)**	Patent Information	D 1,5,10 PI
PN **(1)**	Patent Information and Reissue Patent Number	D PN
RAA	Reassignment Address	D RAA
RAC	Reassigned Country	D 3-6 RAC
RAD	Reassignment Date	D L4 RAD
RAK	Reassignment Kind	D RAK
RED	Reissue Request Date	D RED
REG	Official Gazette Issue Date with Reissue Request	D REG
REX	Reissue Examination Group	D REX
RID	Reinstatement Date	D RID
RIG	Official Gazette Issue Date with Reinstatement Announcement	D RIG
RQD	Reexamination Request Date	D RQD L1
RQG	Official Gazette Issue Date with Reexamination Request	D RQG
RQN	Reexamination Request Number	D RQN
RQR	Reexamination Request Requestor	D RQR 1-3
RRD	Reexamination Request Date	D 2,4,6 RRD
RRN	Reissue Request Number	D RRN
RXD	Reexamination Certificate Date	D 2-4,10 RXD
RXN	Reexamination Numbers	D RXN
RXR	Reexamination Requestor	D RXR
UPCD **(1,2)**	Update Date, Correction Data	D UPCD
UPRAI **(1,2)**	Update Date, Reassignment Information	D UPRAI
UPSTA **(1,2)**	Update Date, Status Information	D UPSTA
XPD	Expiration Date	D 4 XPD
XPG	Official Gazette Issue Date with Expiration Announcement	D XPG
XTD	Extension Date	D XTD
XTG	Official Gazette Issue Date with Extension Announcement	D XTG
ABS	CLM	D L2 ABS
ADI	Adverse Decision Information (AND, ADD, ADG, ADTX)	D L1 ADI 1-2
ALL	AN, PA, PI, DT, CDAT, RID, RIG, XPD, XPG, XTD, XTG, RXI (RXR, RXN, RRD, Certificate Number, RXD), RAI (RAD, RAK, PAO, RAC, RAA), ADI (AND, ADD, ADG, ADTX), DDI (DDD, DDG, DDTX), RQI (RQR, RQN, RQD, RQG), REI (RRN, RED, REG, REX, PN), CLM	D 3 ALL

DISPLAY and PRINT Formats (cont'd)

Format	Content	Examples
BIB (STD)	AN, PA, PI, DT, CDAT, RID, RIG, XPD, XPG, XTD, XTG, RXI (RXR, RXN, RRD, Certificate Number, RXD), RAI (RAD, RAK, PAO, RAC, RAA), ADI (AND, ADD, ADG, ADTX), DDI (DDB, DDG, DDTX), RQI (RQR, RQN, RQD, RQG), REI (RRN, RED, REG, REX, PN) (BIB is the default)	D 1,8 BIB
CBIB	Compressed bibliographic information	D L1 CBIB 2
DDI	Disclaimer/Dedication Information (DDD, DDG, DDTX)	D DDI
IALL	ALL, indented with text labels	D IALL
IBIB	BIB, indented with text labels	D IBIB
ISTD	STD, indented with text labels	D ISTD 1-5
PASS	PA, PAO, RAC	D PASS
RAI	Reassignment Information (RAD, RAK, PAO, RAC, RAA)	D L1 RAI
REI	Reissue Request Information (RRN, RED, REG, REX, PN)	D REI
RQI	Reexamination Request Information (RQR, RQN, RQD, RQG)	D RQI
RXI	Reexamination Information (RXR, RXN, RRD, RXD)	D RXI
STD	BIB	D 1,8 STD
TRIAL (TRI) **(1)**	AN, PI	D 1-5 TRIAL
HIT	Fields containing hit terms	D HIT
KWIC	Hit terms with 20 words on either side (KeyWord-In-Context)	D KWIC
OCC **(1)**	Number of occurrences of hit terms and fields in which they occur	D OCC 1-10

(1) No online display fee for this format.
(2) Custom display only.

SELECT, ANALYZE, and SORT Fields

The SELECT command is used to create E-numbers containing terms taken from the specified field in an answer set.

The ANALYZE command is used to create an L-number containing terms taken from the specified field in an answer set.

The SORT command is used to rearrange the search results in either alphabetic or numeric order of the specified field(s).

Field Name	Field Code	ANALYZE/ SELECT (1)	SORT
Accession Number	AN	Y **(2)**	N
Adverse Decision Date	ADD	Y **(2)**	Y
Adverse Decision Number	ADN	Y	Y
Adverse Decision Text	ADTX	Y **(3)**	N
Claim Text	CLM	Y **(3)**	N
Corporate Source	CS	Y	Y
Correction Date	CDAT	Y **(2)**	Y
Disclaimer/Dedication Date	DDD	Y **(2)**	Y
Disclaimer/Dedication Text	DDTX	Y **(3)**	N
Document Type	DT	Y	Y
Expiration Date	XPD	Y **(2)**	Y
Extension Date	XTD	Y **(2)**	Y
Official Gazette Issue Date with Adverse Decision	ADG	Y **(2)**	Y
Official Gazette Issue Date with Disclaimer/Dedication Date	DDG	Y **(2)**	Y
Official Gazette Issue Date with Expiration Announcement	XPG	Y **(2)**	Y
Official Gazette Issue Date with Extension Announcement	XTG	Y **(2)**	Y
Official Gazette Issue Date with Reexamination Request	RQG	Y **(2)**	Y
Official Gazette Issue Date with Reinstatement Announcement	RIG	Y **(2)**	Y
Official Gazette Issue Date with Reissue Request	REG	Y **(2)**	Y

SELECT, ANALYZE, and SORT Fields (cont'd)

Field Name	Field Code	ANALYZE/ SELECT (1)	SORT
Patent Assignee	PA	Y	Y
Patent Assignee Group	PASS	Y	N
Patent Assignee, Original	PAO	Y **(2)**	Y
Patent Countries	PCS	Y **(2,4)**	N
Patent Country	PC	Y **(2)**	Y
Patent Information	PI	Y **(2,5)**	Y
Patent Number	PN	Y **(2,6)** (default)	Y
	PATS	Y **(2,6)**	N
Publication Date	PD	Y **(2)**	Y
Publication Year	PY	Y **(2)**	Y
Reassignment Agent	RAA	Y **(2)**	Y
Reassignment Company	RAC	Y **(2)**	Y
Reassignment Date	RAD	Y **(2)**	Y
Reassignment Kind	RAK	Y **(2)**	Y
Reexamination Certificate Date	RXD	Y **(2)**	Y
Reexamination Date	RRD	Y **(2)**	Y
Reexamination Number	RXN	Y	Y
Reexamination Request Date	RRD	Y **(2)**	Y
Reexamination Requester	RXR	Y **(2)**	Y
Reexamination Request Date	RQD	Y **(2)**	Y
Reexamination Request Number	RQN	Y	Y
Reexamination Request Requestor	RQR	Y **(2)**	Y
Reinstatement Date	RID	Y **(2)**	Y
Reissue Examination Group	REX	Y **(2)**	Y
Reissue Request Date	RED	Y **(2)**	Y
Reissue Request Number	RRN	Y	Y
Treatment Code	TC	Y	Y
Update Date, Correction Data	UPCD	Y **(2)**	Y
Update Date, Reassignment Information	UPRAI	Y **(2)**	Y
Update Date, Status Information	UPSTA	Y **(2)**	Y

(1) HIT may be used to restrict terms extracted to terms that match the search expression used to create the answer set, e.g., SEL HIT PA.
(2) SELECT HIT and ANALYZE HIT are not valid with this field.
(3) Appends /BI to the terms created by SELECT.
(4) Selects or analyzes PC with /PCS appended to the terms created by SELECT.
(5) Selects or analyzes the patent number with /PN appended to the terms created by SELECT.
(6) Selects or analyzes the patent and reissue patent numbers with /PN appended to the terms created by SELECT.
(7) Selects or analyzes the patent and reissue patent numbers with /PATS appended to the terms created by SELECT.

Sample Records

DISPLAY IALL (Reexamined Patent)
```
ACCESSION NO.:        4047461  IFICLS
PATENT ASSIGNEE:      International Business Machines Corp
PATENT INFORMATION:   US  6718445  20040406
DOCUMENT TYPE:        REEXAMINED; REEXAMINATION REQUESTED;
                      CERTIFICATE OF CORRECTION
CORRECTION DATE:      5 Jul 2005
REEXAMINATION REQUEST:
  REQUESTOR:          International Business Machines Corporation, Armonk, NY
  REQUEST NUMBER:     90/007210
  REQUEST DATE:       20040917
  OG DATE:            20041102
  REQUESTOR:          International Business Machines Corporation, Armonk, NY
  REQUEST NUMBER:     90/007134
  REQUEST DATE:       20041014
  OG DATE:            20041203
REEXAMINATION INFO.:
  REQUESTOR:          International business Machines Corporation  Armonk, NY
                      US
  REQUEST NUMBER:     90/007134
  REQUEST DATE:       20041014
  CERTIFICATE NUMBER: C16718445  (5170th)
  CERTIFICATE DATE:   20050802


                        CLAIM

AS A RESULT OF REEXAMINATION, IT HAS BEEN DETERMINED THAT: The patentability of
claims 1-19 is confirmed. 1. A buffer management system comprising: a buffer
pool further comprised of an amount of fixed storage and an amount of virtual
storage; a target maximum fixed value for the amount of fixed storage, the
target maximum fixed value dynamically alterable by a system administrator; a
target maximum virtual value for the amount of virtual storage, the target
maximum virtual value dynamically alterable by a system administrator; and a
buffer manager for dynamically varying the amount of fixed storage and the
amount of virtual storage based on a comparison of present usage of the amount
of fixed storage and the amount of virtual storage to target maximum fixed and
target maximum virtual values.
```

DISPLAY IALL (Reassigned Patent)
```
ACCESSION NO.:        4297251  IFICLS
PATENT ASSIGNEE:      Wilson, William F
PATENT INFORMATION:   US  6945423  20050920
DOCUMENT TYPE:        REASSIGNED
REASSIGNMENT INFO.:
  DATE:               20050214
  KIND:               ASSIGNMENT OF ASSIGNORS INTEREST
  ASSIGNOR:           WILSON, WILLIAM, DATE SIGNED: 10/04/2004
  ASSIGNEE:           SURGE CONTROL, LLC, 3910 S. INDUSTRIAL AVE., COEUR D'
                      ARLENE, IDAHO, 83815
  AGENT:              MICHAEL S. SMITH, BLACK LOWE & GRAHAM, PLLC, 701 FIFTH
                      AVENUE, SUITE 4800, SEATTLE, WA 98104
  MICROFILM REEL NO:  016264
  MICROFILM FRAME NO: 0279
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DISPLAY IALL (Expired Patent)
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ACCESSION NO.:        2613100  IFICLS
PATENT ASSIGNEE:      Stellmach, Robert N
PATENT INFORMATION:   US  5423083  19950606
DOCUMENT TYPE:        EXPIRED
EXPIRED INFO.:        19990606        OG DATE: 19990803
```

DISPLAY IALL (Reinstated Patent)
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ACCESSION NO.          2048875  IFICLS
PATENT ASSIGNEE:       Testing Machines Inc
PATENT INFORMATION:    US  4928533  19900529
DOCUMENT TYPE:         EXPIRED; REINSTATED
EXPIRED INFO.:         19940529      OG DATE: 19940809
REINSTATEMENT INFO.:   19940803      OG DATE: 19941004
```

DISPLAY ALL (Extended Patent)
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ACCESSION NO.:         2475348  IFICLS
PATENT ASSIGNEE:       Procter & Gamble Co The
PATENT INFORMATION:    US  34617  19940524
DOCUMENT TYPE:         EXTENDED
EXTENDED INFO.:        DATE: 19941201  DESC: (One-year)  OG DATE: 19950214
                       DATE: 19950214  DESC: (Nine (9) months)   OG DATE:
                       19970225
                       DATE: 19960312  DESC: (One year)  OG DATE: 19960312
                       DATE: 19981023  DESC: (two years) OG DATE: 19981201
                       ORIG. EXPIRATION DATE: 19960212, NEW EXPIRATION DATE:
                       19980130
TRADE NAME:            OLEAN (olestra)
```

DISPLAY IALL (Adverse Decision)
```
ACCESSION NO.:         3286429  IFICLS
PATENT ASSIGNEE:       TruTek Inc.
PATENT INFORMATION:    US  5697929  19971216
DOCUMENT TYPE:         ADVERSE DECISION
ADVERSE DECISION IN INTERFERENCE:
  INTERFERENCE NO:     104708
  DECISION DATE:       20031126
  OG DATE:             20030114
  CLAIMS AFFECTED:     as to claims 1, 3-8 and 10-14.
```

DISPLAY IALL (Disclaimer/Dedication)
```
ACCESSION NO.:         3804778  IFICLS
PATENT ASSIGNEE:       Applied materials Inc.
PATENT INFORMATION:    US  6579426  20030617
DOCUMENT TYPE:         DISCLAIMER/DEDICATION
DISCLAIMER INFO.:
  DATE:                20030610
  OG DATE:             20031111
  TEXT:                The term of this patent shall not extend beyond the
                       expiration date of Pat. No. 6,254,738.
```

DISPLAY IALL (Reexamination Requested)
```
ACCESSION NO.:         3523296  IFICLS
PATENT ASSIGNEE:       Apcon Inc.ech Group Inc
PATENT INFORMATION:    US  6243510  20010605
DOCUMENT TYPE:         REEXAMINATION REQUESTED
REEXAMINATION REQUEST:
  REQUESTOR:           Apcon, Inc., Tualatin, OR.
  REQUEST NUMBER:      90/006998
  REQUEST DATE:        200404061
  OG DATE:             20040518
  OG DATE:             19990601
```

DISPLAY IALL (Reissue Request)

```
ACCESSION NO.:          3108309  IFICLS
PATENT ASSIGNEE:        Surgical Innovations LLC
PATENT INFORMATION:     US  5868765  19990209
DOCUMENT TYPE:          REISSUE REQUESTED
REISSUE REQUEST:
  REQUEST NUMBER:       09/299449
  REQUEST DATE:         19990426
  OG DATE:              19990622
  EXAMINATION GROUP:    3731
  PATENT NUMBER:        US 37107
```

DISPLAY ALL (Certificate of Correction)

```
ACCESSION NO.:          3131384  IFICLS
PATENT ASSIGNEE:        NEC Corp JP
PATENT INFORMATION:     US  5889744  19990330
DOCUMENT TYPE:          CERTIFICATE OF CORRECTION
CORRECTION DATE:        1 Jun 1999
```